

# SEMiX703GAR126HDs



SEMiX<sup>®</sup> 3s

## Trench IGBT Modules

### SEMiX703GAR126HDs

#### Features

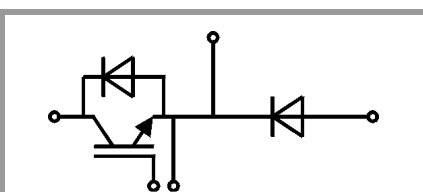
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability
- UL recognised file no. E63532

#### Typical Applications\*

- AC inverter drives
- UPS
- Electronic Welding

#### Remarks

- Case temperatur limited to  $T_C=125^\circ\text{C}$  max.
- Not for new design



GAR

Absolute Maximum Ratings				
Symbol	Conditions		Values	Unit
<b>IGBT</b>				
$V_{CES}$	$T_j = 25^\circ\text{C}$		1200	V
$I_C$	$T_j = 150^\circ\text{C}$	$T_c = 25^\circ\text{C}$	642	A
		$T_c = 80^\circ\text{C}$	449	A
$I_{Cnom}$			450	A
$I_{CRM}$	$I_{CRM} = 2 \times I_{Cnom}$		900	A
$V_{GES}$			-20 ... 20	V
$t_{psc}$	$V_{CC} = 600\text{ V}$	$T_j = 125^\circ\text{C}$	10	$\mu\text{s}$
	$V_{GE} \leq 20\text{ V}$			
	$V_{CES} \leq 1200\text{ V}$			
$T_j$			-40 ... 150	$^\circ\text{C}$
<b>Inverse diode</b>				
$I_F$	$T_j = 150^\circ\text{C}$	$T_c = 25^\circ\text{C}$	561	A
		$T_c = 80^\circ\text{C}$	384	A
$I_{Fnom}$			450	A
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$		900	A
$I_{FSM}$	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$		2900	A
$T_j$			-40 ... 150	$^\circ\text{C}$
<b>Freewheeling diode</b>				
$I_F$	$T_j = 150^\circ\text{C}$	$T_c = 25^\circ\text{C}$	533	A
		$T_c = 80^\circ\text{C}$	367	A
$I_{Fnom}$			450	A
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$		900	A
$I_{FSM}$	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$		2900	A
$T_j$			-40 ... 150	$^\circ\text{C}$
<b>Module</b>				
$I_{t(RMS)}$	$T_{terminal} = 80^\circ\text{C}$		600	A
$T_{stg}$			-40 ... 125	$^\circ\text{C}$
$V_{isol}$	AC sinus 50Hz, $t = 1\text{ min}$		4000	V

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>IGBT</b>						
$V_{CE(sat)}$	$I_C = 450\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.7	2.1		V
		$T_j = 125^\circ\text{C}$	2.0	2.45		V
$V_{CE0}$		$T_j = 25^\circ\text{C}$	1	1.2		V
		$T_j = 125^\circ\text{C}$	0.9	1.1		V
$r_{CE}$	$V_{GE} = 15\text{ V}$	$T_j = 25^\circ\text{C}$	1.6	2.0		$\text{m}\Omega$
		$T_j = 125^\circ\text{C}$	2.4	3.0		$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 18\text{ mA}$		5	5.8	6.5	V
$I_{CES}$	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_j = 25^\circ\text{C}$	0.1	0.3		$\text{mA}$
		$T_j = 125^\circ\text{C}$				$\text{mA}$
$C_{ies}$	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	32.3			$\text{nF}$
$C_{oes}$		$f = 1\text{ MHz}$	1.69			$\text{nF}$
$C_{res}$		$f = 1\text{ MHz}$	1.46			$\text{nF}$
$Q_G$	$V_{GE} = -8\text{ V...} + 15\text{ V}$		3600			$\text{nC}$
$R_{Gint}$	$T_j = 25^\circ\text{C}$		1.67			$\Omega$

# SEMiX703GAR126HDs



SEMiX® 3s

## Trench IGBT Modules

### SEMiX703GAR126HDs

#### Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability
- UL recognised file no. E63532

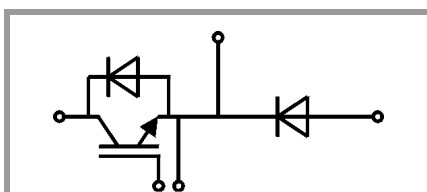
#### Typical Applications\*

- AC inverter drives
- UPS
- Electronic Welding

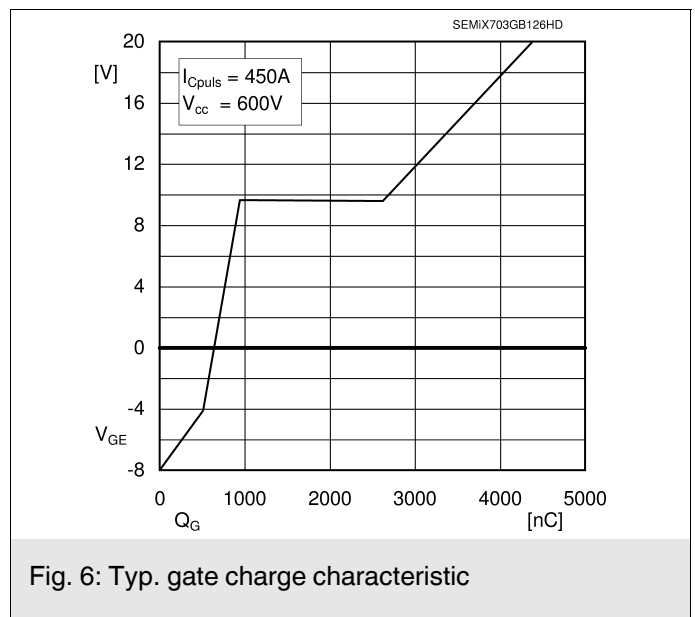
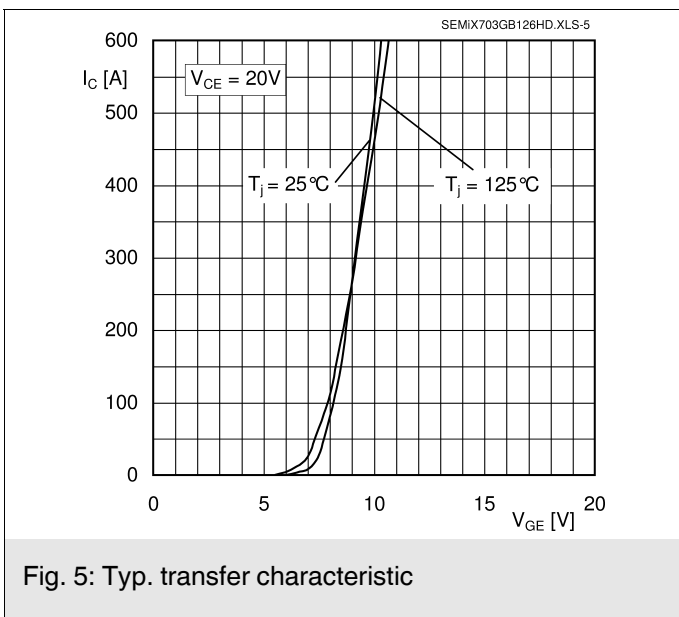
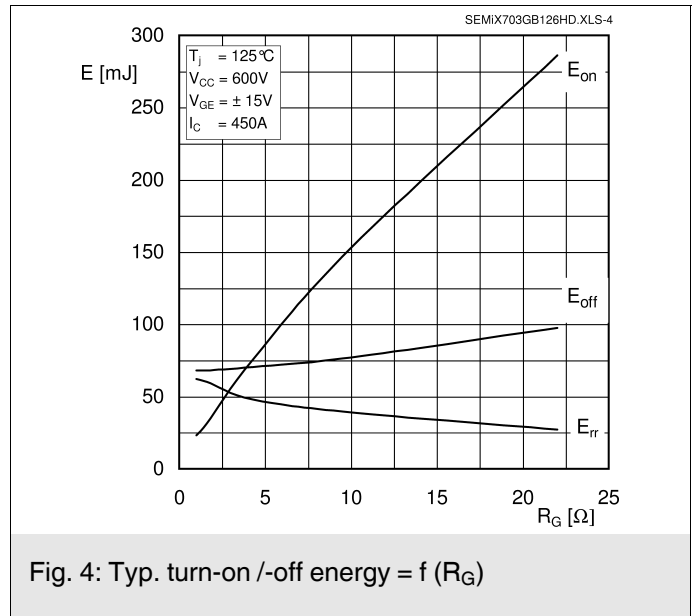
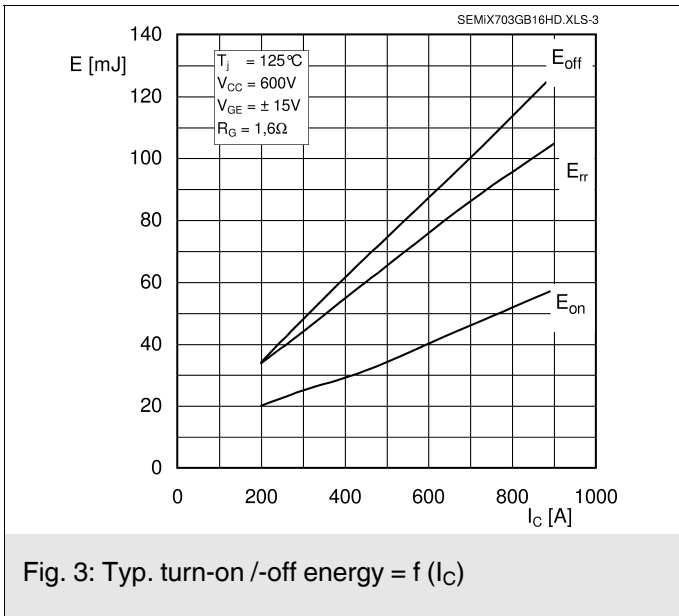
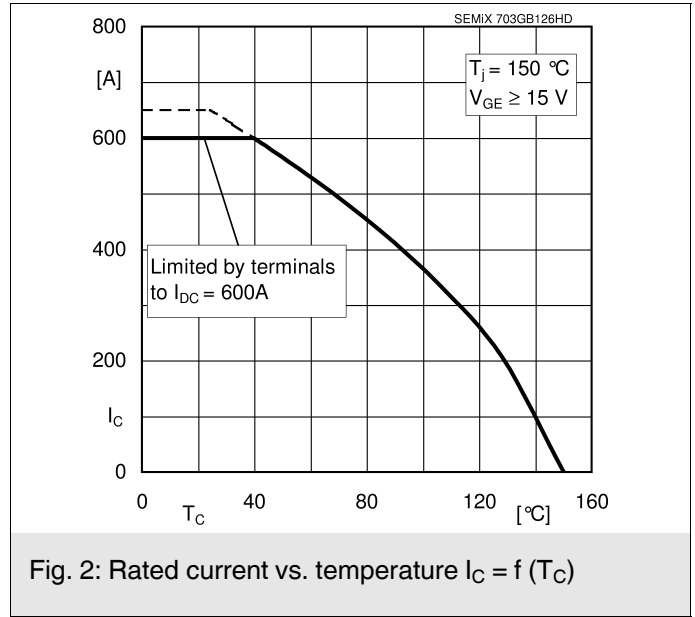
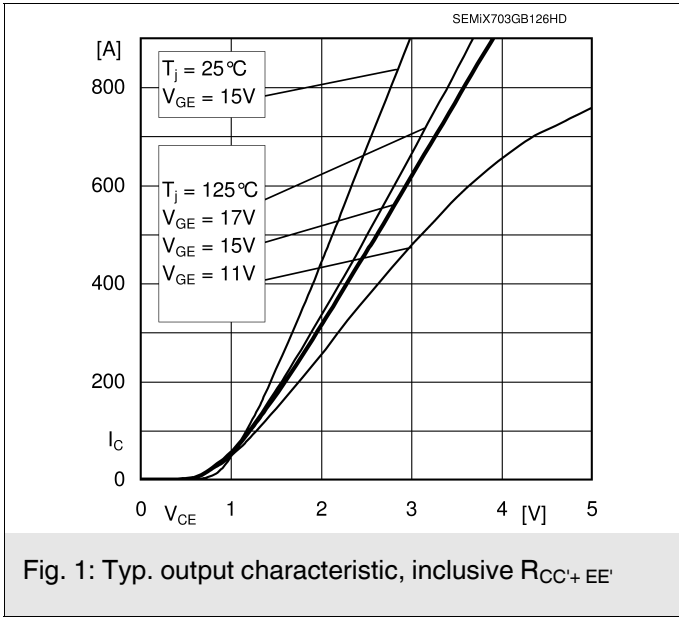
#### Remarks

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
- Not for new design

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
$t_{d(on)}$	$V_{CC} = 600\text{ V}$	$T_j = 125^\circ\text{C}$		310		ns
$t_r$	$I_C = 450\text{ A}$	$T_j = 125^\circ\text{C}$		60		ns
$E_{on}$	$V_{GE} = \pm 15\text{ V}$	$T_j = 125^\circ\text{C}$		32		mJ
$t_{d(off)}$	$R_{G\ on} = 1.6\ \Omega$	$T_j = 125^\circ\text{C}$		680		ns
$t_f$	$R_{G\ off} = 1.6\ \Omega$	$T_j = 125^\circ\text{C}$		135		ns
$E_{off}$		$T_j = 125^\circ\text{C}$		68		mJ
$R_{th(j-c)}$	per IGBT				0.061	K/W
Inverse diode						
$V_F = V_{EC}$	$I_F = 450\text{ A}$	$T_j = 25^\circ\text{C}$		1.6	1.80	V
	$V_{GE} = 0\text{ V}$ chip	$T_j = 125^\circ\text{C}$		1.6	1.8	V
$V_{F0}$		$T_j = 25^\circ\text{C}$	0.9	1	1.1	V
		$T_j = 125^\circ\text{C}$	0.7	0.8	0.9	V
$r_F$		$T_j = 25^\circ\text{C}$	1.1	1.3	1.6	m $\Omega$
		$T_j = 125^\circ\text{C}$	1.6	1.8	2.0	m $\Omega$
$I_{RRM}$	$I_F = 450\text{ A}$	$T_j = 125^\circ\text{C}$		580		A
$Q_{rr}$	$di/dt_{off} = 8500\text{ A}/\mu\text{s}$	$T_j = 125^\circ\text{C}$		130		$\mu\text{C}$
$E_{rr}$	$V_{GE} = -15\text{ V}$	$T_j = 125^\circ\text{C}$		60		mJ
	$V_{CC} = 600\text{ V}$	$T_j = 125^\circ\text{C}$				
$R_{th(j-c)}$	per diode				0.11	K/W
Freewheeling diode						
$V_F = V_{EC}$	$I_F = 450\text{ A}$	$T_j = 25^\circ\text{C}$		1.7	1.91	V
	$V_{GE} = 0\text{ V}$ chip	$T_j = 125^\circ\text{C}$		1.7	1.9	V
$V_{F0}$		$T_j = 25^\circ\text{C}$	0.9	1	1.1	V
		$T_j = 125^\circ\text{C}$	0.7	0.8	0.9	V
$r_F$		$T_j = 25^\circ\text{C}$	1.3	1.5	1.8	m $\Omega$
		$T_j = 125^\circ\text{C}$	1.8	2.1	2.3	m $\Omega$
$I_{RRM}$	$I_F = 450\text{ A}$	$T_j = 125^\circ\text{C}$		580		A
$Q_{rr}$	$di/dt_{off} = 8500\text{ A}/\mu\text{s}$	$T_j = 125^\circ\text{C}$		130		$\mu\text{C}$
$E_{rr}$	$V_{GE} = -15\text{ V}$	$T_j = 125^\circ\text{C}$		60		mJ
	$V_{CC} = 600\text{ V}$	$T_j = 125^\circ\text{C}$				
$R_{th(j-c)}$	per diode				0.11	K/W
Module						
$L_{CE}$				20		nH
$R_{CC+EE}$	res., terminal-chip	$T_C = 25^\circ\text{C}$		0.7		m $\Omega$
		$T_C = 125^\circ\text{C}$		1		m $\Omega$
$R_{th(c-s)}$	per module			0.04		K/W
$M_s$	to heat sink (M5)		3		5	Nm
$M_t$		to terminals (M6)	2.5		5	Nm
						Nm
$w$					300	g
Temperatur Sensor						
$R_{100}$	$T_C = 100^\circ\text{C}$ ( $R_{25} = 5\text{ k}\Omega$ )			$493 \pm 5\%$		$\Omega$
$B_{100/125}$	$R(T) = R_{100} \exp[B_{100/125}(1/T - 1/T_{100})]$ ; $T[\text{K}]$ ;			$3550 \pm 2\%$		K



GAR



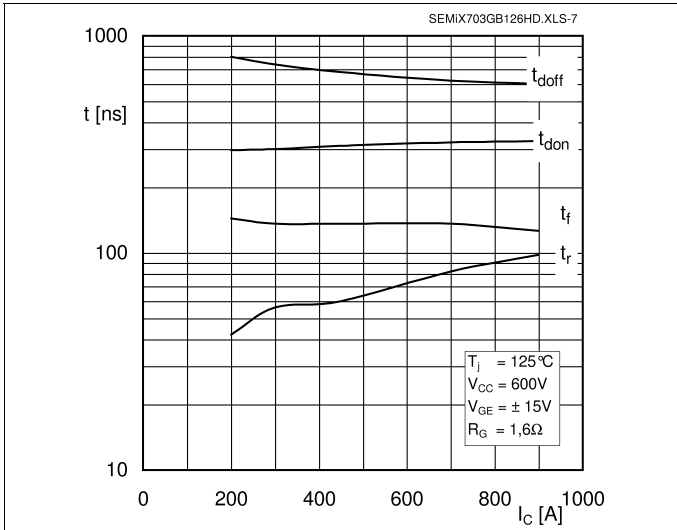


Fig. 7: Typ. switching times vs.  $I_C$

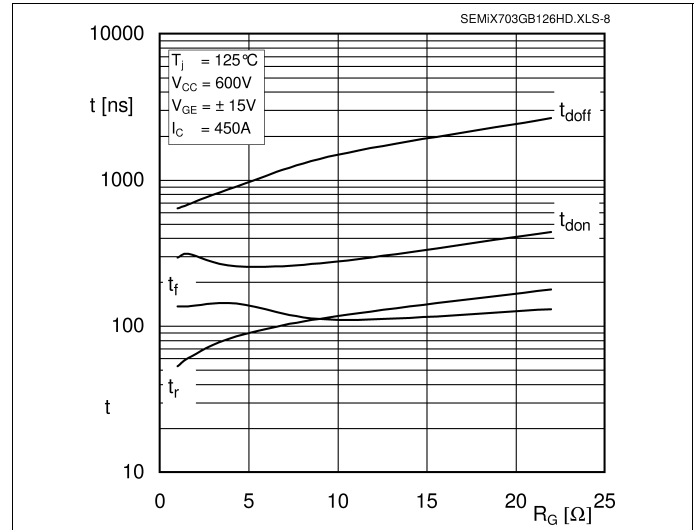


Fig. 8: Typ. switching times vs. gate resistor  $R_G$

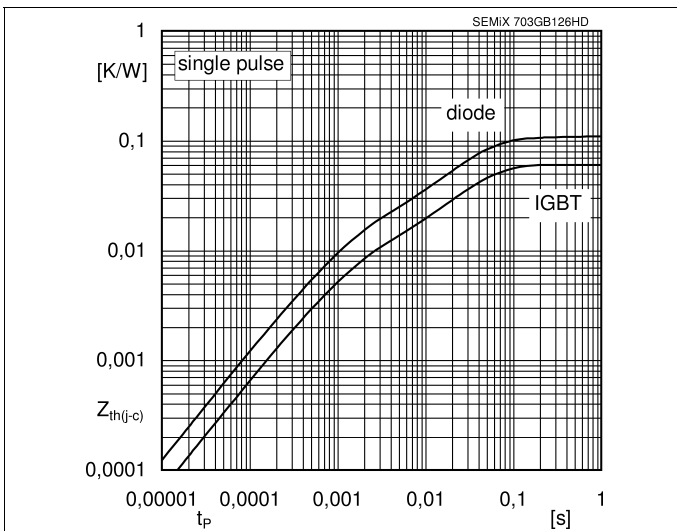


Fig. 9: Typ. transient thermal impedance

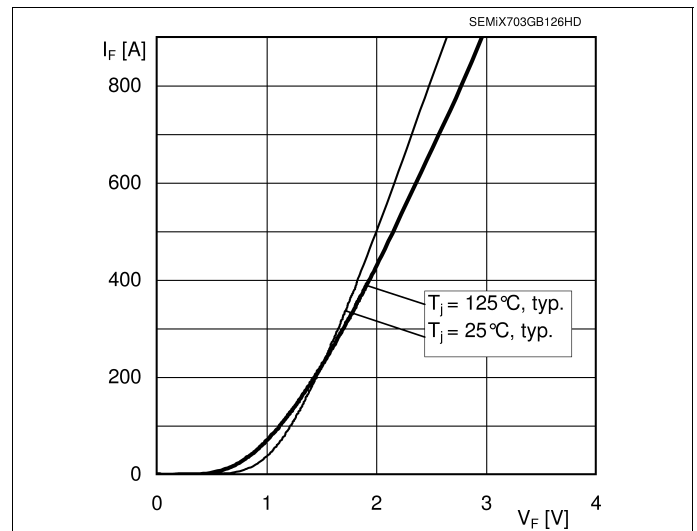


Fig. 10: Typ. CAL diode forward charact., incl.  $R_{CC+EE}$

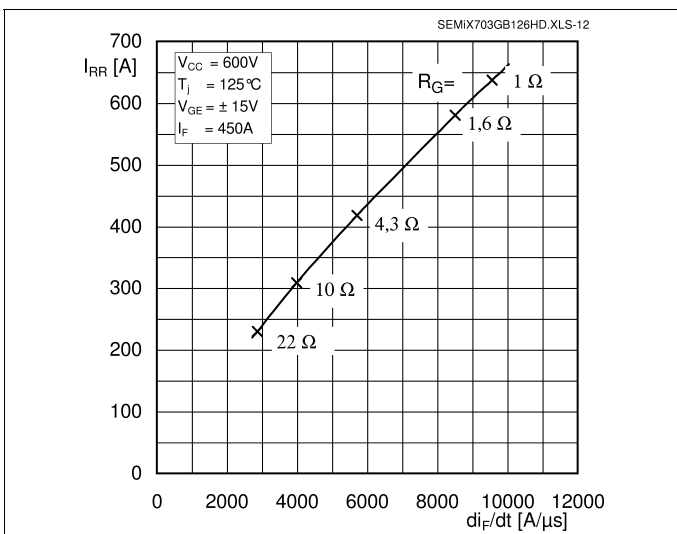


Fig. 11: Typ. CAL diode peak reverse recovery current

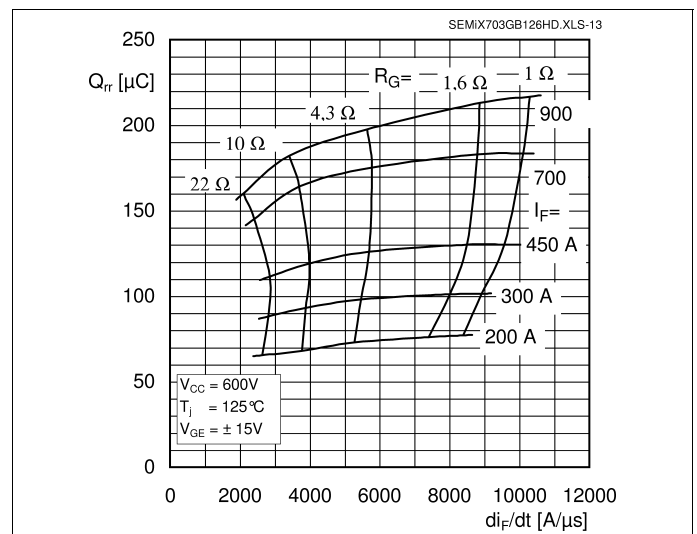
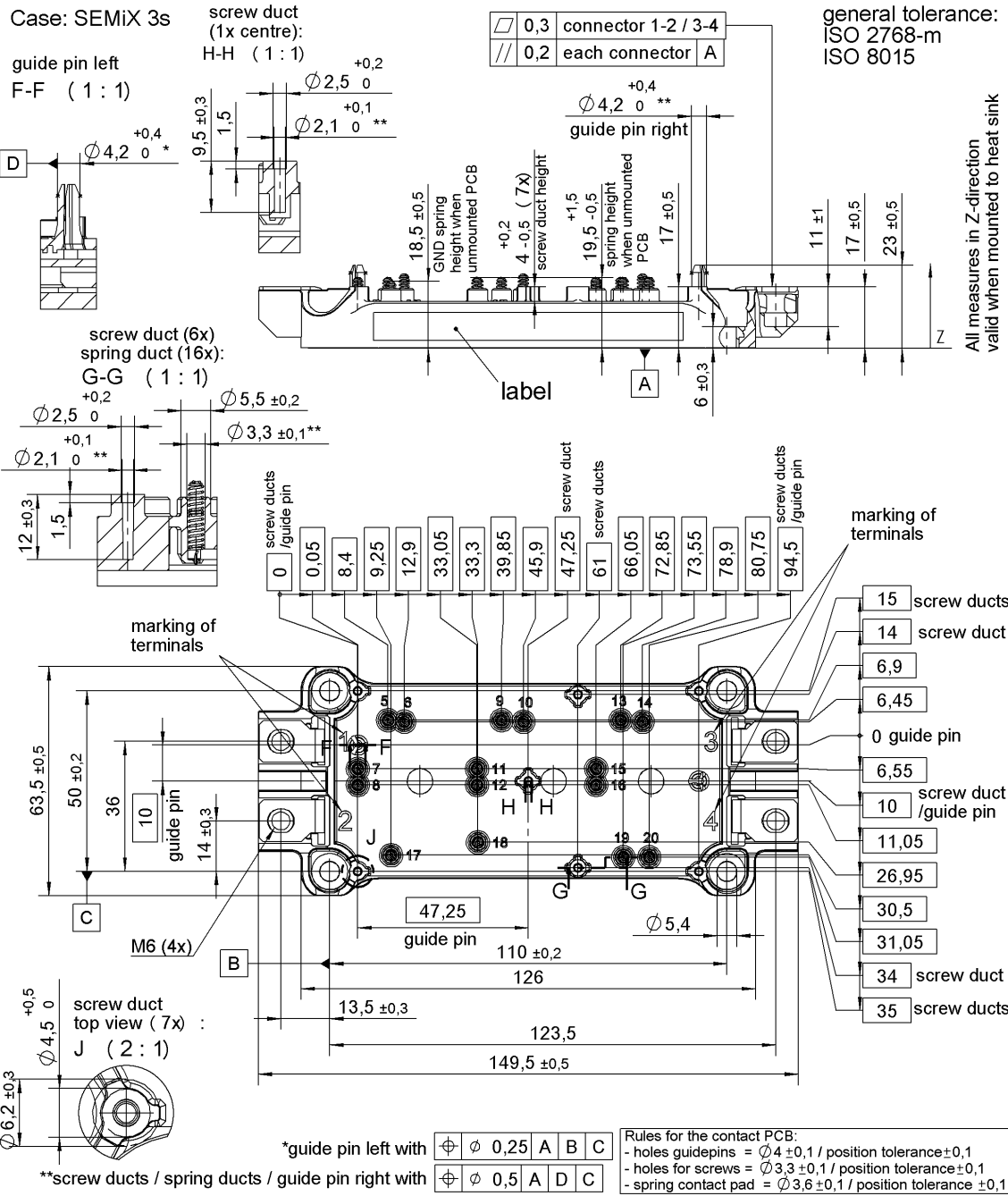
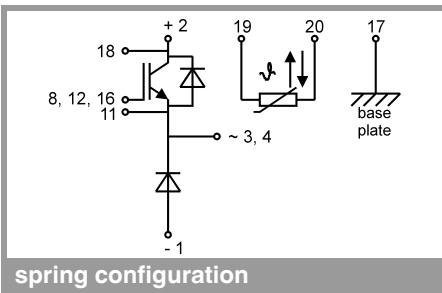


Fig. 12: Typ. CAL diode recovery charge

# SEMiX703GAR126HDs



SEMIX 3s



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

\* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our staff.